



Yves Joly Curriculum Vitae

Date of birth: April 24th, 1959, 63 years old
Place and of birth: Sète, at the Mediterranean
Sea side, France
Nationality: French
4 children

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WEB page: <https://neel.cnrs.fr/les-chercheurs-et-techniciens/yves-joly>

1976 Bachelor, Auch, France

1982 Engineer in Physics (ENSPG, Grenoble)
DEA *Physical Science of Matter and Radiation*, UJF, Grenoble, France

1984 PhD in *Physical science of Matter and Radiation*
Done at Laboratoire de Spectrométrie-Physique, UJF, Grenoble, France
and at the Royal Institute of Technology, Stockholm, Sweden

1985 Post-Doc at the CHU at Sherbrooke, Québec, Canada

1986 Permanent position at CNRS as Junior Researcher 2nd class, team *Surface* at Laboratoire de Spectrométrie-Physique, Grenoble, France

1986 9 months stay at INIFTA, La Plata, Argentina

1990 Junior Researcher 1st class

1993 Move to *Laboratoire de Cristallographie*, Grenoble, France

1995 Diploma *Habilitation à Diriger des Recherches*

2006 Senior Researcher 2nd class

2007 Move to Institut Néel, Grenoble, team *Theory and numerical Simulations of electronic properties*

2010 Change of team to *Surfaces Interfaces and Nanostructures* (SIN)

2011 – 2015: Deputy director of the MCMF department at Institut Néel, CNRS

2014 Senior Researcher 1st class

2018-2022 Head of the SIN team

Main research fields

1986 – 1997:

- Study of the surface of nitrides and carbides, experimentally and theoretically with low energy electron diffraction (LEED). Study of semi-conductors surfaces with low energy positron diffraction (LEPD).
- Development of an *ab initio* computational code to simulate LEED and LEPD using the finite difference method.

From 1998:

- Theoretical study of x-ray absorption spectroscopies, and more specifically in the energy range close to the absorption edges (XANES), in dichroism, resonant diffraction, x-ray emission spectroscopy and x-ray Raman Spectroscopy.
- Development of the *ab initio* simulation software FDMNES (Finite Difference Method Near Edge Structures). Strong effort to make a user-friendly tool and for its dissemination. Web site: <https://fdmnes.neel.cnrs.fr>
- Application to the study of many classes of materials and special interest for transition metal oxides and their electronic properties

157 publications.

6 Chapters in text books

Collaboration with many teams in France and abroad

Participation at the conferences: XAFS9 (1996, Grenoble), XAFS12 (2002, Malmö), XAFS13 (2006, Stanford), XAFS14 (2009, Camerino), XAFS15 (2012, Beijing), XAFS16 (2015, Karlsruhe), XAFS17 (2018, Cracovia), XAFS18 (2022, Sydney).

Teaching

Many courses and practical in general physics, optics, mathematics and solid-state physics.

Many workshops and tutorial in x-ray absorption spectroscopies (4-5 per year from 20 years)
Most in France but also in Great Britain, Germany, USA, Argentina, Canada, Russia, ...